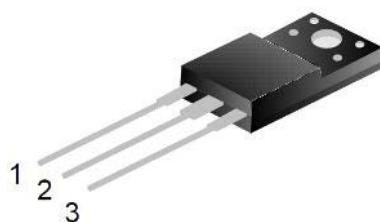


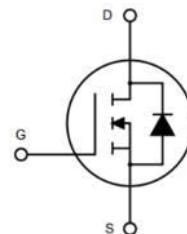
800V N-Channel MOSFET

Main Product Characteristics:

| | |
|---------------|-------------|
| $V_{(BR)DSS}$ | 800V |
| $R_{DS(ON)}$ | 0.42Ω(max.) |
| I_D | 12A |



TO-220F



Schematic Diagram

Features and Benefits

- Grand Turbo MOSFET process technology.
- Optimized the cell structure.
- Low on-resistance and low gate charge.
- Featuring low switching and drive losses.
- Fast switching and reverse body recovery.
- High ruggedness and robustness.



Description

The GT series products utilizes Trust's outstanding standard turbo process and packaging techniques to achieve ultralow on-resistance and low gate charge and to provide the industry's best-in-class performance.

These features make this series products extremely efficient, temperature characteristics and reliable for use in power management, synchronous rectification, battery protection, load switch and a wide variety of other applications.

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Parameter. | Unit |
|--|-----------------------------------|--------------|---------------------|
| Drain-Source Voltage | V_{DS} | 800 | V |
| Gate-to-Source Voltage | V_{GS} | ± 30 | V |
| Continuous Drain Current, @ Steady-State | I_D @ $T_C = 25^\circ\text{C}$ | 12 | A |
| Continuous Drain Current, @ Steady-State | I_D @ $T_C = 100^\circ\text{C}$ | 7.6 | A |
| Pulsed Drain Current | I_{DM} | 48 | A |
| Power Dissipation | P_D @ $T_C = 25^\circ\text{C}$ | 36 | W |
| | | 0.29 | W/ $^\circ\text{C}$ |
| Single Pulse Avalanche Energy ¹ | E_{AS} | 510 | mJ |
| Body diode reverse voltage slope ² | dv/dt | 50 | V/ns |
| MOS dv/dt ruggedness ³ | dv/dt | 100 | V/ns |
| Junction-to-Ambient (PCB Mounted, Steady-State) | $R_{\theta JA}$ | 62.5 | $^\circ\text{C/W}$ |
| Junction-to-Case | $R_{\theta JC}$ | 3.5 | $^\circ\text{C/W}$ |
| Operating Junction and Storage Temperature Range | T_J/T_{STG} | -55 to + 150 | $^\circ\text{C}$ |



800V N-Channel MOSFET

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|---------------------------------------|-----------------------------|---|------|------|------|---------------|
| Drain-to-Source Breakdown Voltage | $V_{(\text{BR})\text{DSS}}$ | $V_{GS}=0\text{V}, I_D=250\mu\text{A}$ | 800 | - | - | V |
| Drain-to-Source Leakage Current | I_{DSS} | $V_{DS}=800\text{V}, V_{GS}=0\text{V}$ | - | - | 1 | μA |
| Gate-to-Source Forward Leakage | I_{GSS} | $V_{DS}=0\text{V}, V_{GS}=30\text{V}$ | - | - | 100 | nA |
| | | $V_{DS}=0\text{V}, V_{GS}=-30\text{V}$ | - | - | -100 | |
| Static Drain-to-Source On- Resistance | $R_{DS \text{ (on)}}$ | $V_{GS}=10\text{V}, I_D=6.0\text{A}$ | - | 0.36 | 0.42 | Ω |
| Gate Threshold Voltage | $V_{GS \text{ (th)}}$ | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 2.4 | - | 4.6 | V |
| Gate Resistance | R_g | $f=1\text{MHz}$ | - | 6.4 | - | Ω |
| Input Capacitance | C_{iss} | $V_{GS}=0\text{V} V_{DS}=100\text{V}, f=1\text{MHz}$ | - | 1130 | - | pF |
| Output Capacitance | C_{oss} | | - | 36 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 1.9 | - | |
| Total Gate Charge 4,5 | Q_g | $I_D=12\text{A}, V_{DD}=640\text{V}, V_{GS}=10\text{V}$ | - | 30 | - | nC |
| Gate-to-Source Charge 4,5 | Q_{gs} | | - | 9.5 | - | |
| Gate-to-Drain("Miller") Charge 4,5 | Q_{gd} | | - | 12 | - | |
| Turn-on Delay Time 4,5 | $t_{d(on)}$ | $V_{DD}=400\text{V}, V_{GS}=10\text{V}, R_G=25\Omega, I_D=12\text{A}$ | - | 24 | - | nS |
| Rise Time 4,5 | t_r | | - | 57 | - | |
| Turn-Off Delay Time 4,5 | $t_{d(off)}$ | | - | 80 | - | |
| Fall Time 4,5 | t_f | | - | 36 | - | |

Source-Drain Ratings and Characteristics

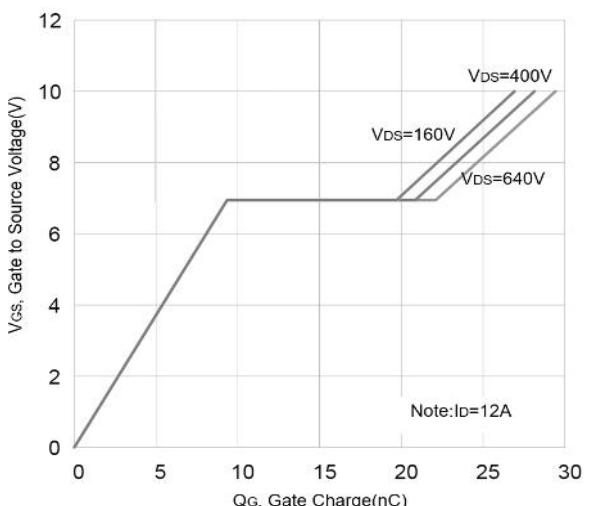
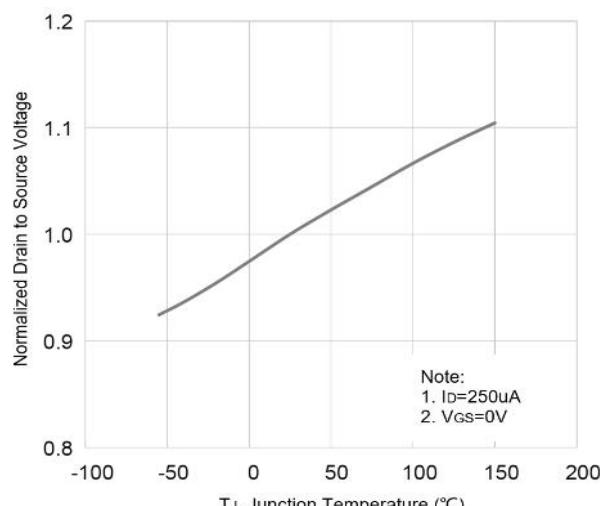
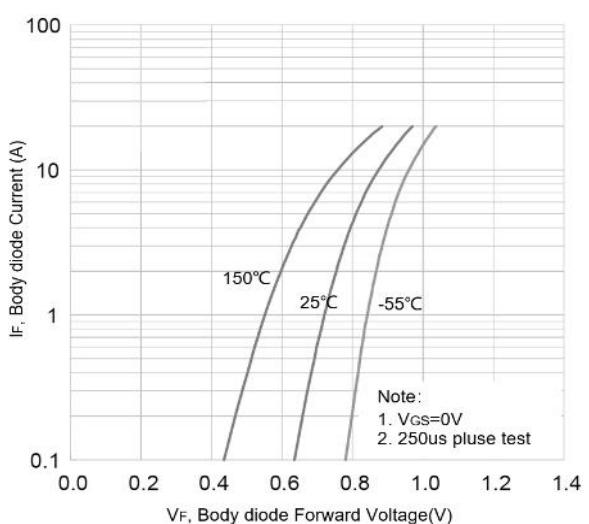
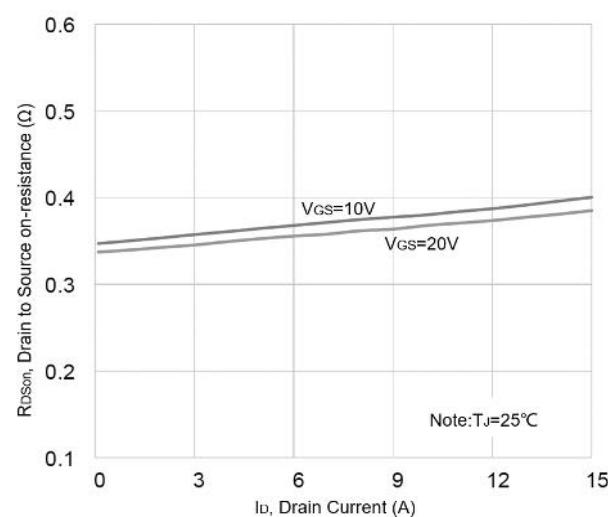
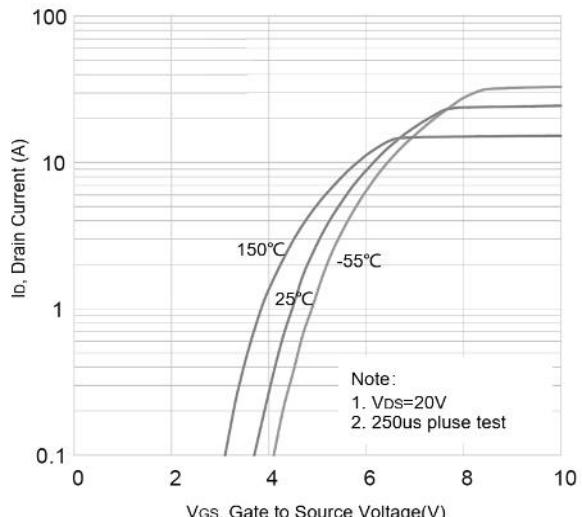
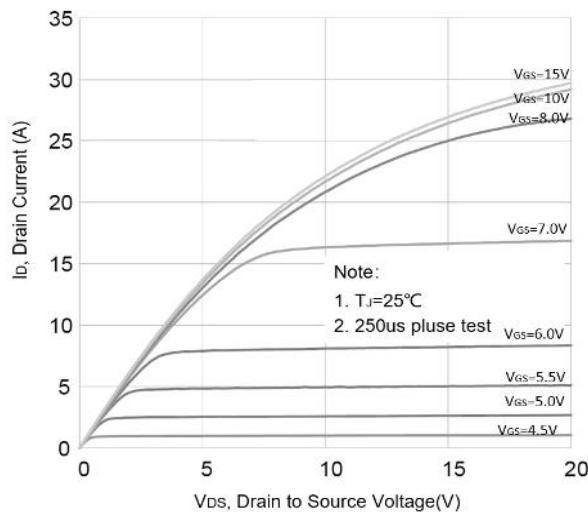
| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|--|----------|---|------|------|------|---------------|
| Continuous Source Current (Body Diode) | I_s | $T_C=25^\circ\text{C}$, MOSFET symbol showing the integral reverse p-n junction diode. | - | - | 12 | A |
| Source Pulse Current | I_{SM} | | - | - | 48 | A |
| Diode Forward Voltage | V_{SD} | $I_s=12\text{A}, V_{GS}=0\text{V}$ | - | 1.1 | 1.4 | V |
| Reverse Recovery Time 2 | t_{rr} | $I_F=12\text{A}, V_{GS}=0\text{V}, dI_F/dt=100\text{A}/\mu\text{s}$ | - | 391 | - | nS |
| Reverse Recovery Charge 2 | Q_{rr} | | - | 4.5 | - | μC |

Notes:

1. $L=79\text{mH}, I_{AS}=3.4\text{A}, V_{DD}=100\text{V}, R_g=25\Omega$, starting temperature $T_J=25^\circ\text{C}$.
2. $V_{DS}=0\text{--}400\text{V}, I_{SD} \leq I_s, T_J=25^\circ\text{C}$.
3. $V_{DS}=0\text{--}480\text{V}$.
4. Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
5. Essentially Independent of Operating Tempera.

800V N-Channel MOSFET

Typical Electrical and Thermal Characteristic Curves



800V N-Channel MOSFET

Typical Electrical and Thermal Characteristic Curves

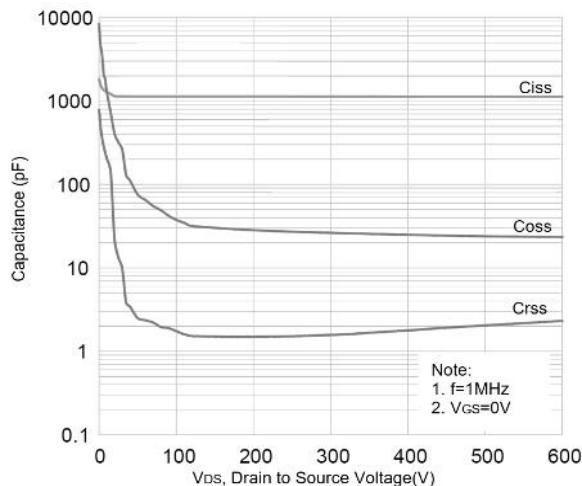


Figure7. Capacitance Characteristic

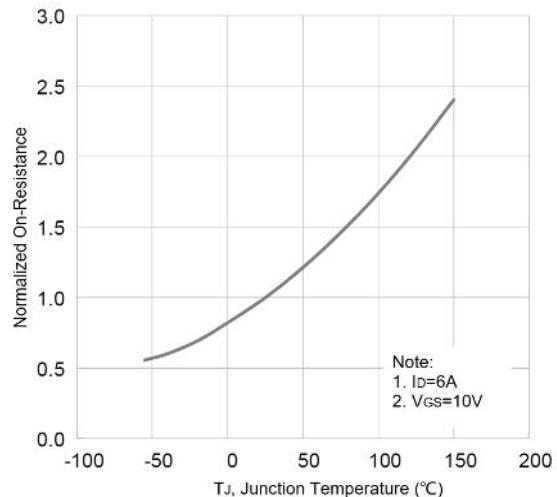


Figure8. Normalized R_{dson} vs. T_J

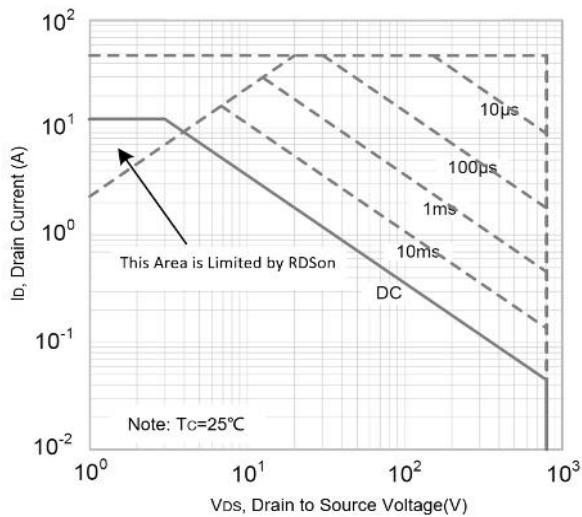


Figure9. Safe Operation Area

800V N-Channel MOSFET

Test Circuit & Waveform

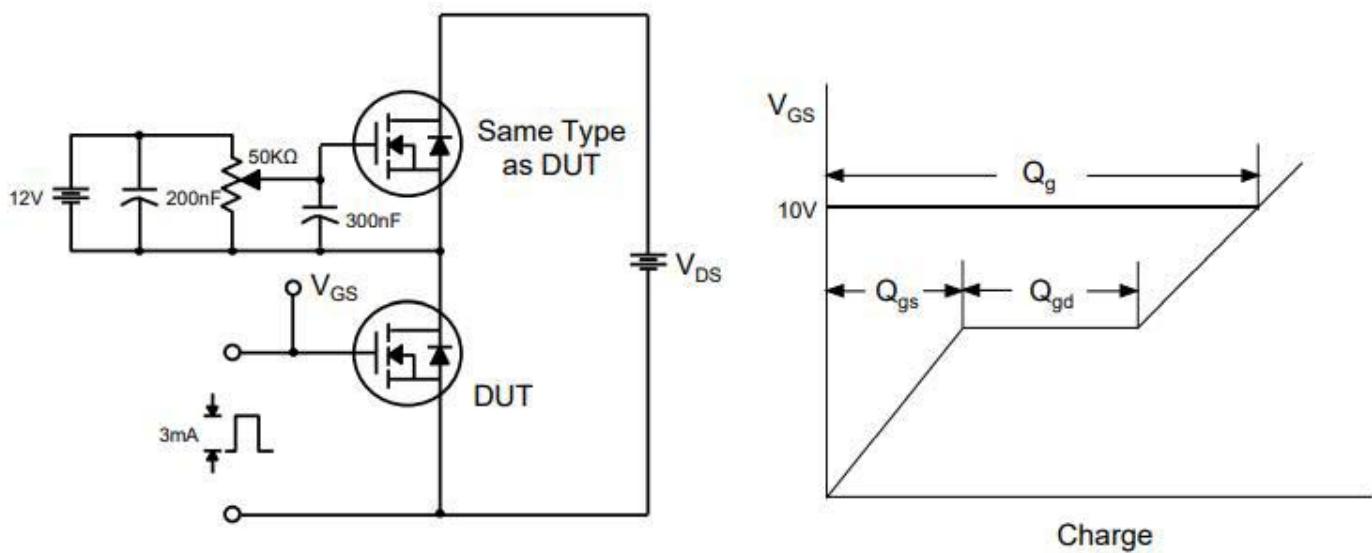


Figure 10. Gate Charge Test Circuit & Waveforms

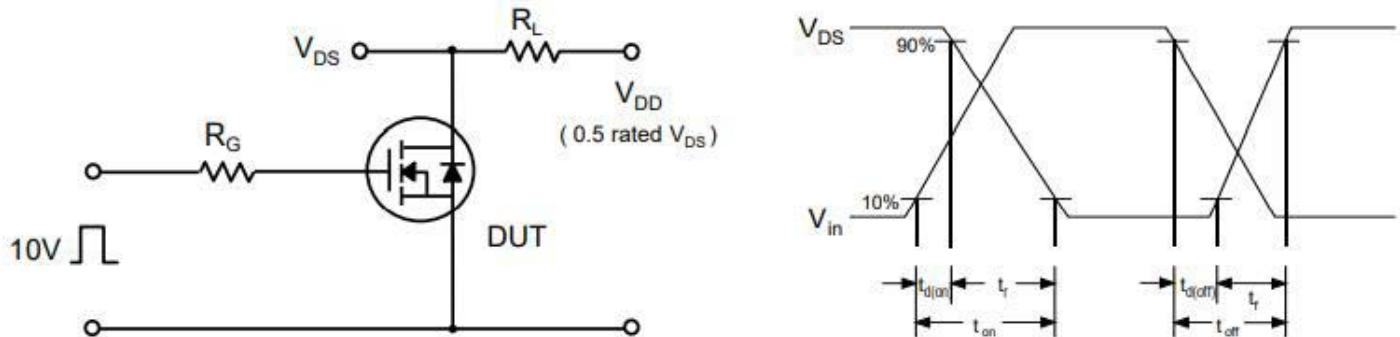


Figure 11. Resistive Switching Test Circuit & Waveforms

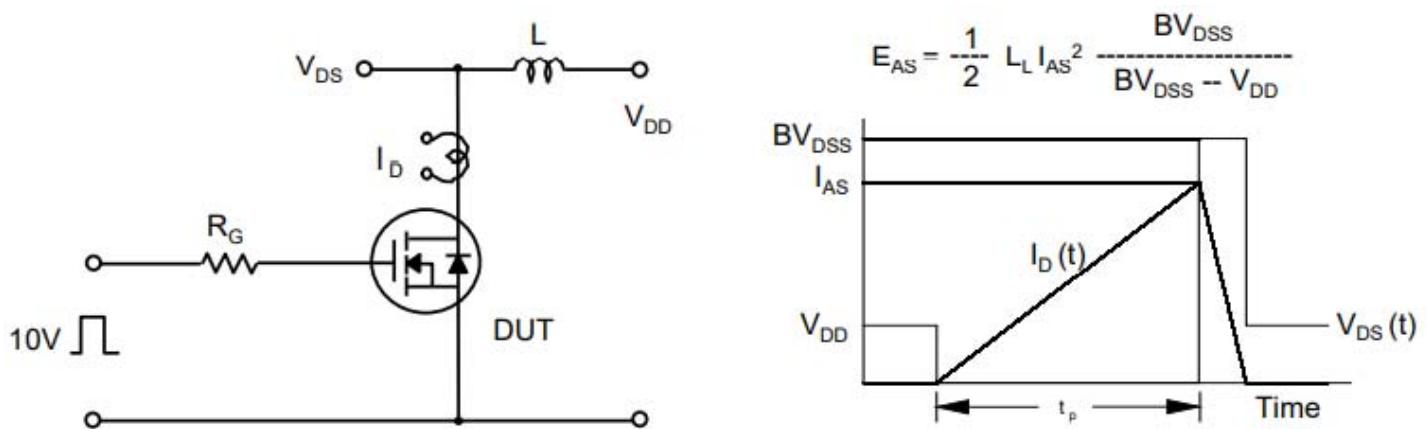
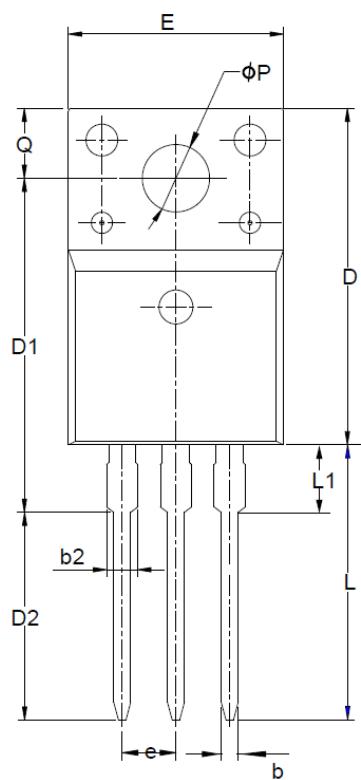


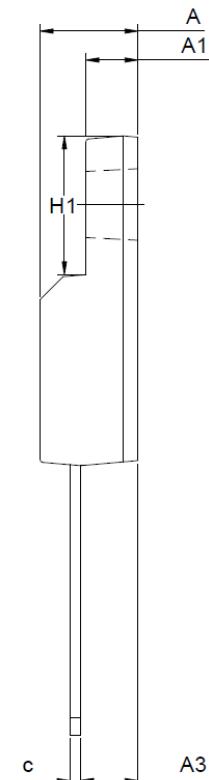
Figure 12. Unclamped Inductive Switching Test Circuit & Waveforms

800V N-Channel MOSFET

Package Outline Dimensions



TO-220F



| SYMBOL | MILLIMETER | | |
|--------|------------|-------|-------|
| | MIN | NOM | MAX |
| A | 4.42 | 4.70 | 5.02 |
| A1 | 2.30 | 2.54 | 2.80 |
| A3 | 2.50 | 2.76 | 3.10 |
| b | 0.70 | 0.80 | 0.90 |
| b2 | — | — | 1.47 |
| c | 0.35 | 0.50 | 0.65 |
| D | 15.25 | 15.87 | 16.25 |
| D1 | 15.30 | 15.75 | 16.30 |
| D2 | 9.30 | 9.80 | 10.30 |
| E | 9.73 | 10.16 | 10.36 |
| e | 2.54BSC | | |
| H1 | 6.40 | 6.68 | 7.00 |
| L | 12.48 | 12.98 | 13.48 |
| L1 | — | — | 3.50 |
| φP | 3.00 | 3.18 | 3.40 |
| Q | 3.05 | 3.30 | 3.55 |